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IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re the Application of: **Kenji WATANABE et al.**

Serial No.: **Not yet assigned**

(§371 of international application No. PCT/JP2004/000711)

Filed: **July 25, 2005**

For: **MAPPING-PROJECTION-TYPE ELECTRON BEAM APPARATUS
FOR INSPECTING SAMPLE BY USING ELECTRONS EMITTED
FROM THE SAMPLE**

Attorney Docket Number: **052886**

Customer Number: **38834**

INFORMATION DISCLOSURE STATEMENT

Commissioner for Patents
P. O. Box 1450
Alexandria, VA 22313-1450

Date: July 25, 2005

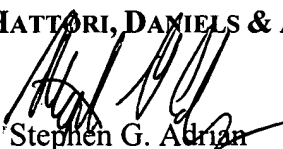
Sir:

In compliance with 37 C.F.R. §1.56, Applicants direct the attention of the Patent and Trademark Office to the documents listed on the attached PTO/SB/08 and cited in the enclosed international search report. Since the documents were cited in the international search report, it is believed that copies of the documents have been transmitted by the International Bureau.

In the event there are any fees due in connection with the filing of this paper, please charge Deposit Account No. 50-2866.

Respectfully submitted,

WESTERMAN, HATTORI, DANIELS & ADRIAN, LLP


Stephen G. Adrian

Attorney for Applicants

Registration No. 32,878

Telephone: (202) 822-1100

Facsimile: (202) 822-1111

SGA/yap

Enclosure: PTO/SB/08 and International Search Report

Combined Form PTO/SB/08A&B <u>INFORMATION DISCLOSURE</u> <u>STATEMENT BY APPLICANT</u> <i>(use as many sheets as necessary)</i>				<i>Complete if Known</i>	
				Application Number	New Application
				Confirmation Number	
				Filing Date	July 25, 2005
				First Named Inventor	Kenji WATANABE et al.
				Art Unit	
Examiner Name					
Sheet	1	of	1	Attorney Docket Number	052886

U.S. PATENT DOCUMENTS					
Examiner Initials*	Cite No. ¹	Document Number		Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document
		Number	Kind Code ² (if known)		
		US			
		US			
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FOREIGN PATENT DOCUMENTS							
Examiner Initials*	Cite No. ¹	Foreign Patent Document			Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Translation ⁶
		Country Code ³	Number ⁴	Kind Code ⁵ (if known)			
	1	PCT	WO 99/46798		09-16-1999	Hitachi Ltd.	
	2	EPO	0 949 653		10-13-1999	Hitachi Instruments Eng. et al.	
	3	JP	2002-141013		05-17-2002	Hitachi Ltd.	
	4	PCT	WO 00/72355		11/30/2000	KLA Tencor Corp. et al.	

NON PATENT LITERATURE DOCUMENTS			
Examiner Initials*	Cite No. ¹	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city, and/or country where published.	Translation ⁶
	5	"Electron Energy Discriminator for Wafer Chip Testing", IBM Technical Disclosure Bulletin, Vol. 23, No.6, November 1, 1980, pp.2288-2290.	
	6	W. ZHU et al.; "Large Current Density from Carbon Nanotube Field Emitters", Applied Physics Letters, Vol. 75, No. 6, pp.873-875.	

Examiner Signature		Date Considered	
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*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

¹Applicant's unique citation designation number (optional). ²See Kind Codes of USPTO Patent Documents at www.uspto.gov, MPEP 901.04 or in the comment box of this document. ³Enter Office that issued the document, by the two-letter code (WIPO Standard ST. 3). ⁴For Japanese patent documents, the indication of the year of the reign of the Emperor must precede the serial number of the patent document. ⁵Kind of document by the appropriate symbols as indicated on the document under WIPO Standard ST. 16 if possible. ⁶Applicant is to indicate here if English language Translation is attached.